## Notice of References Cited Application/Control No. 10/735,334 Examiner CongVan Tran Applicant(s)/Patent Under Reexamination LUNDH ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,722,078 A	02-1998	Przelomiec et al.	455/434
*	В	US-6,219,352 B1	04-2001	Bonomi et al.	370/417
*	С	US-6,421,328 B1	07-2002	Larribeau et al.	370/329
*	D	US-6,917,809 B2	07-2005	Horwath et al.	455/436
*	E	US-5,970,407 A	10-1999	Brunner et al.	455/437
*	F	US-5,666,650	09-1997	Turcotte et al.	370/329
*	G	US-2002/0102994 A1	08-2002	Tuutijarvi, Mika	455/456
*	н	US-2004/0203882 A1	10-2004	Laiho et al.	455/456.1
*	1	US-2004/0204097	10-2004	Scheinert et al.	455/561
	J	US-			
	К	US-			•
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Ρ					
	σ					
	R					
	Ø					
	Т			•		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	·					
	V						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.